

PATENT

DK-US065116

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of
Junko TAKAHASHI et al.
Serial No.: New – (National Phase of
PCT/JP2004/017779)
International filing date: November 30, 2004
For: METHOD OF EXAMINING CHEMICAL
USING GENE-DISRUPTED STRAIN

INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner of Patents
Washington, DC 20231

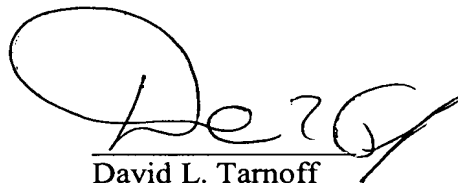
Sir:

In accordance with MPEP 609 and 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicants bring the references listed on the attached PTO-1449-Form to the Examiner's attention and request that they be considered and made of record in this application. Copies of the non-U.S. patents are attached.

* * *

Prompt examination on the merits is respectfully requested.

Respectfully submitted,


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